

Search Notes

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10/776,618

Examiner

Le Nguyen

Applicant(s)/Patent under
Reexamination

CHIU ET AL.

Art Unit

2174

SEARCHED

Class	Subclass	Date	Examiner
715	734	9/22/2007	LVN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
US-PGPub, USPAT: 715/734		9/22/2007	LVN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
inventor name search	9/22/2007	LVN
IEEE, Xplore, JPO, EPO	9/24/2007	LVN
US-PGPub, USPAT: 715/708,734,850,853-855	9/24/2007	LVN
consulted w/Ba Huynh	9/24/2007	LVN